



Product Change Notification / JAON-26WRWL960

Date:

28-Feb-2022

Product Category:

P-Channel Enhancement Mode MOSFETs

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4884 Final Notice: Qualification of CEL-8240 GS as a new mold compound material for selected Supertex TP0604N3-G catalog part number (CPN) available in 3L TO-92 package assembled at CRTK assembly site.

Affected CPNs:

[JAON-26WRWL960_Affected_CPN_02282022.pdf](#)

[JAON-26WRWL960_Affected_CPN_02282022.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of CEL-8240 GS as a new mold compound material for selected Supertex TP0604N3-G catalog part number (CPN) available in 3L TO-92 package assembled at CRTK assembly site.

Pre and Post Change Summary:

Implementation Date																			
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Method to Identify Change:Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

October 30, 2021: Issued initial notification.

February 28, 2022: Issued final notification. Attached the Qualification Report. Provided estimated first ship date to be on March 31, 2022.

The change described in this PCN does not alter Microchip’s current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_JAON-26WRWL960_QUAL_REPORT.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

TP0604N3-G



QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN#: JAON-26WRWL960

Date
February 18, 2022

Qualification of CEL-8240 GS as a new mold compound material for selected Supertex TP0604N3-G catalog part number (CPN) available in 3L TO-92 package assembled at CRTK assembly site.



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PACKAGE QUALIFICATION REPORT

Purpose	Qualification of CEL-8240 GS as a new mold compound material for selected Supertex TP0604N3-G catalog part number (CPN) available in 3L TO-92 package assembled at CRTK assembly site.
CN	E000083444
QUAL ID	R2101195 (Rev. A)
MP CODE	630339A2XG00
Part No.	TP0604N3-G
Bonding No.	BD-000286 Rev 02
CCB No.	4884
<u>Package</u>	
Type	3L-TO-92
<u>Lead Frame</u>	
Paddle size	140 x 100 mils
Material	ALLOY 194
Surface	Ag
Process	Stamping
Lead Lock	No
Part Number	TO03NH2105
<u>Die attach material</u>	
Epoxy	84-1LMISR4
Wire	Au wire
Mold Compound	CEL-8240 GS
Plating Composition	Matte Sn



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PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
CRTK223300001.000	SPTX915142175.800	21451AG
CRTK223300002.000	SPTX915142175.800	21451B7
CRTK223300003.000	SPTX915142175.800	21451B8

Result ☒ Pass ☐ Fail ☐ _____

3L-TO-92 assembled by CRTK pass reliability test per QCI-39000.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Electrical Test	Electrical Test: +25°C System: ETS300	JESD22-A113	693(0)	693		Good Devices
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Inspection: External crack inspection all units under 40X Optical magnification Electrical Test: +25°C System: ETS300 Bond Strength: Wire Pull (> 5.00 grams) Bond Shear (> 25.00 grams)	JESD22-A104	231(0)	231 0/231	Pass	77 units / lot
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X Electrical Test: +25°C System: ETS300	JESD22-A118	231(0)	231 0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 30 Volts System: HAST 6000X Electrical Test: +25°C System: ETS300	JESD22-A110	231(0)	231 0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB Electrical Test: +25°C System: ETS300	JESD22-A103	45(0)	45 0/45	Pass	45 units
Solderability Temp 245°C	Steam Aging: Temp 93°C, 8Hrs System: SAS-3000 Solder Dipping: Solder Temp. 245°C Solder material: Pb Free Sn 95.5Ag3.9Cu0.6 System: ERS A 2200D Visual Inspection: External Visual Inspection	JESD22B-102E	22(0)	22 22 0/22	Pass	
Wire sweep	Wire sweep Inspection 15 Wires / lot	-	45(0) Wires	0/45	Pass	
Physical Dimensions	Physical Dimension, 10 units from 1 lot	JESD22-B100/B108	30(0) Units	0/30	Pass	
Lead Integrity	15 Leads from a minimum of 5 units, 1 lot. System: Strain	JESD22-B105D	15(0) Leads	0/15	Pass	
Bond Strength Data Assembly	Wire Pull (> 5.00 grams) Bond Shear (> 25.00 grams)	Mil. Std. 883-2011	30(0) Wires 30(0) bonds	0/30 0/30	Pass Pass	